1	Application/Control No.	Applicant(s)/Patent unde Reexamination	r
	10/816,058	BAGWELL, J. BRIAN	
Γī	Examiner	Art Unit	
	Jimmy T. Nguyen	3725	

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SEARCHED						
Class	Subclass	Date	Examiner			
100	35, 100, 214,265 226,229A	9/7/2005	NTL			
100	299	9/7 <i>1</i> 2005	JTN			
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EAST and inventor name search	9/8/2005	JTN
Text search in class 414 and 241 (see print out)	9/8 <i>1</i> 2005	ИТL
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